Form PTO 1449 (Modified)	449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 250738US2CONT		SERIAL NO. New CONT Application		
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LIST OF	REFE	RENCES CITED BY AF	PLICANT	Yoshinori OKUMURA, et al.		10/814270		
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FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		
TSP	AO	2000-353803	12/19/2000	Japan (w/Enlish Abstract)		x		
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K. IMAI, et al., IEDM, pages 455-458, "CMOS DEVICE OPTIMIZATION FOR SYSTEM-ON-A-CHIP APPLICATIONS," 2000								
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	AZ			Additional Referen			ces she	et(s) attached
Examiner			DU.		Date Considered 9130/04			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								